ON Semiconductor

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MOSFET – N-Channel, QFET®

1000 V, 8.0 A, 1.45 Ω

FQH8N100C

Description

This N-Channel enhancement mode power MOSFET is produced using ON Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.

Features

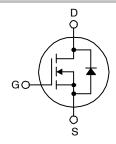
- 8 A, 1000 V, $R_{DS(on)} = 1.45 \Omega$ (Max.) @ $V_{GS} = 10 \text{ V}$
- Low Gate Charge (Typ. 53 nC)
- Low Crss (Typ. 16 pF)
- Fast Switching
- 100% Avalanche Tested
- Improved dv/dt Capability
- This Device is Pb-Free and is RoHS Compliant



ON Semiconductor®

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V _{DS}	R _{DS(ON)} MAX	I _D MAX	
1000 V	1.45 Ω @ 10 V	8 A	

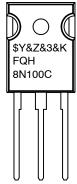


N-CHANNEL MOSFET



TO-247-3LD CASE 340CK

MARKING DIAGRAM



\$Y = ON Semiconductor Logo &Z = Assembly Plant Code &3 = Numeric Date Code &K = Lot Code FQH8N100C = Specific Device Code

ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

ABSOLUTE MAXIMUM RATINGS ($T_C = 25^{\circ}C$ unless otherwise noted)

Symbol	Parameter		FQH8N100C	Unit
V _{DSS}	Drain-Source Voltage		1000	V
I _D	Drain Current:	Continuous (T _C = 25°C)	8.0	Α
		Continuous (T _C = 100°C)	5.0	
I _{DM}	Drain Current:	Pulsed (Note 1)	32	Α
V _{GSS}	Gate-Source Voltage		±30	V
E _{AS}	Single Pulsed Avalanche Energy (Note 2)		850	mJ
I _{AR}	Avalanche Current (Note 1)		8.0	А
E _{AR}	Repetitive Avalanche Energy (Note 1)		22	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		4.0	V/ns
P_{D}	Power Dissipation	T _C = 25°C	225	W
		Derate Above 25°C	1.79	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to + 150	°C
TL	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 seconds		300	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- 1. Repetitive rating: Pulse–width limited by maximum junction temperature. 2. L = 25 mH, I_{AS} = 8.0 A, V_{DD} = 50 V, R_{G} = 25 Ω , Starting T_{J} = 25°C 3. $I_{SD} \le 8.0$ A, di/dt ≤ 200 A/ μ s, $V_{DD} \le BV_{DSS}$, Starting T_{J} = 25°C.

PACKAGE MARKING AND ORDERING INFORMATION

Part Number	Top Marking	Package	Packing Method	Reel Size	Tape Width	Quantity
FQH8N100C	FQH8N100C	TO-247	Tube	N/A	N/A	30 Units

THERMAL CHARACTERISTICS

Symbol	Parameter	FQH8N100C	Unit
$R_{ heta JC}$	Thermal Resistance, Junction to Case, Max.	0.56	°C/W
$R_{ hetaJA}$	Thermal Resistance, Junction to Ambient, Max.	40	

ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted)

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Unit
OFF CHARA	ACTERISTICS			-	-	
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V, } I_D = 250 \mu\text{A}$	1000	_	_	V
$\Delta BV_{DSS} / \Delta T_{J}$	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C	-	1.4	_	V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 1000 V, V _{GS} = 0 V	<u> </u>	_	10	μΑ
		V _{DS} = 800 V, T _C = 125 °C	_	_	100	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V	_	_	100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	-100	nA
ON CHARA	CTERISTICS					
V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	3.0	_	5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 4.0 A	_	1.2	1.45	Ω
9FS	Forward Transconductance $V_{DS} = 50 \text{ V}, I_D = 4.0 \text{ A}$		<u> </u>	8.0	_	S
DYNAMIC C	HARACTERISTICS			-	-	
C _{iss}	Input Capacitance	V _{DS} = 25 V, V _{GS} = 0 V, f = 1.0 MHz	_	2475	3220	pF
C _{oss}	Output Capacitance	7	_	195	255	pF
C _{rss}	Reverse Transfer Capacitance	7	_	16	21	pF
SWITCHING	CHARACTERISTICS	•				
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 500 \text{ V}, I_D = 8.0 \text{ A},$	_	50	110	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$ (Note 4)	_	95	200	ns
t _{d(off)}	Turn-Off Delay Time		_	122	254	ns
t _f	Turn-Off Fall Time	7	_	80	170	ns
Qg	Total Gate Charge	$V_{DS} = 800 \text{ V}, I_D = 8.0 \text{ A}, V_{GS} = 10 \text{ V}$	_	53	70	nC
Q _{gs}	Gate-Source Charge	(Note 4)	_	13	_	nC
Q _{gd}	Gate-Drain Charge	7	_	23	_	nC
DRAIN-SOU	IRCE DIODE CHARACTERISTICS AND MA	AXIMUM RATINGS				
IS	Maximum Continuous Source-Drain Diode Forward Current		_	-	8.0	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current		-	-	32.0	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 8.0 \text{ A}$	<u> </u>	-	1.4	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _S = 8.0 A,	<u> </u>	620	-	ns
Q _{rr}	Reverse Recovery Charge	dl _F /dt = 100 A/μs	_	5.2	_	μС

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Essentially independent of operating temperature.

TYPICAL PERFORMANCE CHARACTERISTICS

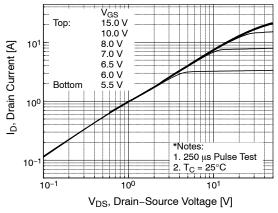


Figure 1. On-Region Characteristics

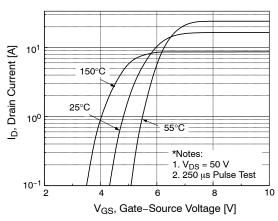


Figure 2. Transfer Characteristics

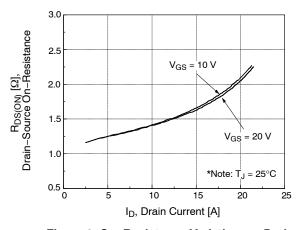


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

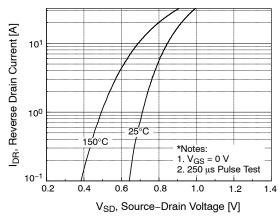


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

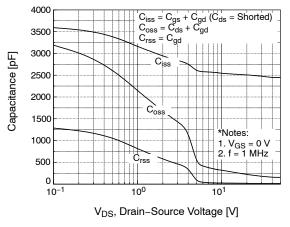


Figure 5. Capacitance Characteristics

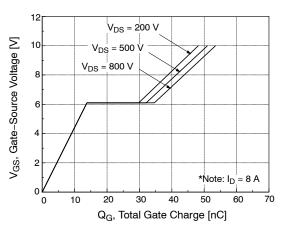


Figure 6. Gate Charge Characteristics

TYPICAL PERFORMANCE CHARACTERISTICS (continued)

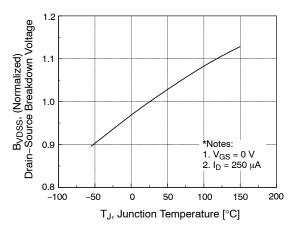


Figure 7. Breakdown Voltage Variation vs. Temperature

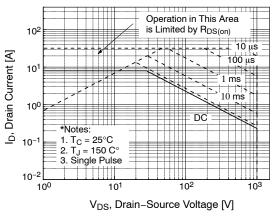


Figure 9. Maximum Safe Operating Area

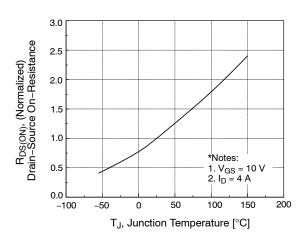


Figure 8. On–Resistance Variation vs. Temperature

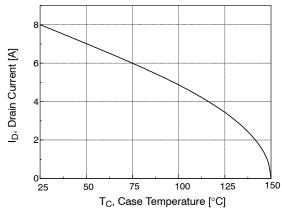


Figure 10. Maximum Drain Current vs. Case Temperature

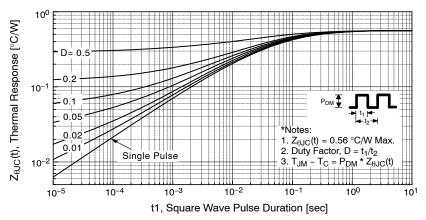


Figure 11. Transient Thermal Response Curve

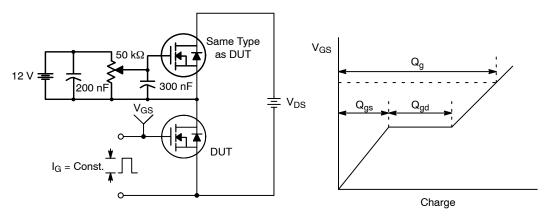


Figure 12. Gate Charge Test Circuit & Waveform

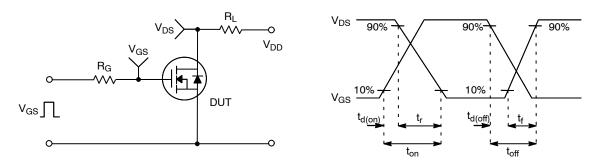


Figure 13. Resistive Switching Test Circuit & Waveforms

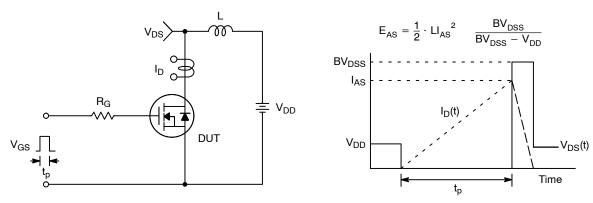


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms

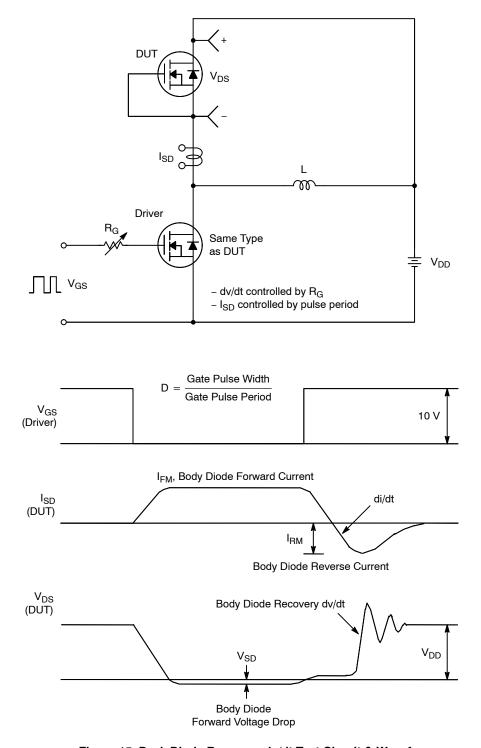
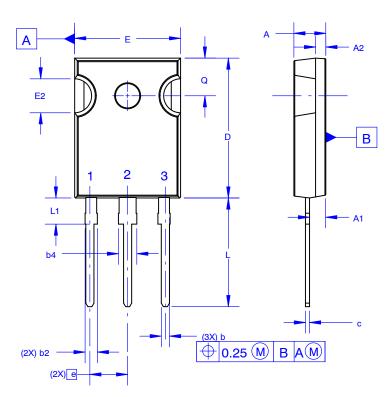


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms

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TO-247-3LD SHORT LEAD

CASE 340CK ISSUE A





- A. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.
- B. ALL DIMENSIONS ARE IN MILLIMETERS.
- C. DRAWING CONFORMS TO ASME Y14.5 2009.
- D. DIMENSION A1 TO BE MEASURED IN THE REGION DEFINED BY L1.
- E. LEAD FINISH IS UNCONTROLLED IN THE REGION DEFINED BY L1.

GENERIC MARKING DIAGRAM*



XXXX = Specific Device Code

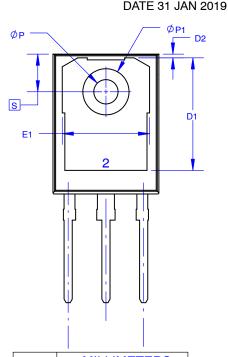
A = Assembly Location

Y = Year

WW = Work Week

ZZ = Assembly Lot Code

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.



DIM	MIL	LIMET	ERS
DIIVI	MIN	NOM	MAX
Α	4.58	4.70	4.82
A1	2.20	2.40	2.60
A2	1.40	1.50	1.60
b	1.17	1.26	1.35
b2	1.53	1.65	1.77
b4	2.42	2.54	2.66
С	0.51	0.61	0.71
D	20.32	20.57	20.82
D1	13.08	~	~
D2	0.51	0.93	1.35
E	15.37	15.62	15.87
E1	12.81	?	~
E2	4.96	5.08	5.20
е	~	5.56	~
L	15.75	16.00	16.25
L1	3.69	3.81	3.93
ØΡ	3.51	3.58	3.65
Ø P1	6.60	6.80	7.00
Q	5.34	5.46	5.58
S	5.34	5.46	5.58

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DESCRIPTION:	TO-247-3LD SHORT LEAD		PAGE 1 OF 1

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